

<b>Notice of References Cited</b>	Application/Control No. 09/954,475	Applicant(s)/Patent Under Re examination GEN-EI ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-US006452880B1		
	B	US-		
	C	US-		
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	F	US-		
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**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 63175490 A	07-1988	Japan	NAKADA et al. H01S 03/18
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**NON-PATENT DOCUMENTS**

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